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<b>PAPER TITLE</b>	<b>AUTHOR(S)</b>	<b>VIEW PRESENTATION</b>
<b>Advances in Sn-Ag-Cu and Sn-Ag-Cu-X Alloy Development for Pb-free Electronic Solder Applications</b>	<i>Iver E. Anderson, Joel Haringa, Jason Walleser and David Rehbein, Iowa State University</i>	<a href="#">Launch Presentation</a>
<b>Interfacial Evolution between Solder and Metallization</b>	<i>Kwang-Lung Lin, National Cheng-Kung University</i>	<a href="#">Launch Presentation</a>
<b>Alternate Pb Free Solder Alloys for High Strain Rate Mechanical Loading Conditions</b>	<i>Ahmer Syed, Amkor Technology</i>	<a href="#">Launch Presentation</a>
<b>Conductive Anodic Filament Formation</b>	<i>Laura J. Turbini, University of Toronto</i>	<a href="#">Launch Presentation</a>
<b>Nano-Enabled Low Temperature Lead-free Solders for Advanced Electronic Packaging</b>	<i>Alan Rae, Gregory Berube and Suv Sengupta, NanoDynamics, Inc.,</i>	<a href="#">Launch Presentation</a>
<b>Challenges of Densification in Electronics Packages and Assembly</b>	<i>Fay Hua, Intel Corporation</i>	<a href="#">Launch Presentation</a>